

## SANYO Semiconductors DATA SHEET

An ON Semiconductor Company

P-Channel Silicon MOSFET

# **3LP01S** — General-Purpose Switching Device **Applications**

#### **Features**

- · Low ON-resistance.
- · Ultrahigh-speed switching.
- 2.5V drive.

### **Specifications**

#### Absolute Maximum Ratings at Ta=25°C

Parameter	Symbol	Conditions	Ratings	Unit
Drain-to-Source Voltage	VDSS		-30	V
Gate-to-Source Voltage	VGSS		±10	V
Drain Current (DC)	ID		-0.1	Α
Drain Current (Pulse)	IDP	PW≤10µs, duty cycle≤1%	-0.4	Α
Allowable Power Dissipation	PD		0.15	W
Channel Temperature	Tch		150	°C
Storage Temperature	Tstg		-55 to +150	°C

#### Electrical Characteristics at Ta=25°C

Parameter	Symbol	Conditions	Ratings			l loit
			min	typ	max	Unit
Drain-to-Source Breakdown Voltage	V(BR)DSS	I <sub>D</sub> =-1mA, V <sub>G</sub> S=0V	-30			V
Zero-Gate Voltage Drain Current	IDSS	VDS=-30V, VGS=0V			-1	μΑ
Gate-to-Source Leakage Current	IGSS	V <sub>GS</sub> =±8V, V <sub>DS</sub> =0V			±10	μΑ
Cutoff Voltage	VGS(off)	V <sub>DS</sub> =-10V, I <sub>D</sub> =-100μA	-0.4		-1.4	V
Forward Transfer Admittance	yfs	VDS=-10V, ID=-50mA	80	110		mS
Static Drain-to-Source On-State Resistance	R <sub>DS</sub> (on)1	ID=-50mA, VGS=-4V		8	10.4	Ω
	R <sub>DS</sub> (on)2	ID=-30mA, VGS=-2.5V		11	15.4	Ω
	RDS(on)3	ID=-1mA, VGS=-1.5V		27	54	Ω
Input Capacitance	Ciss	V <sub>DS</sub> =-10V, f=1MHz		7.5		pF
Output Capacitance	Coss	V <sub>DS</sub> =-10V, f=1MHz		5.7		pF
Reverse Transfer Capacitance	Crss	V <sub>DS</sub> =-10V, f=1MHz		1.8		pF
Turn-ON Delay Time	t <sub>d</sub> (on)	See specified Test Circuit.		24		ns
Rise Time	t <sub>r</sub>	See specified Test Circuit.		55		ns
Turn-OFF Delay Time	t <sub>d</sub> (off)	See specified Test Circuit.		120		ns
Fall Time	t <sub>f</sub>	See specified Test Circuit.		130		ns

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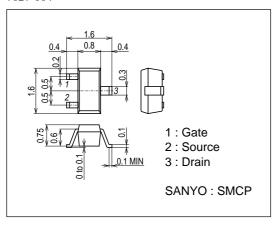
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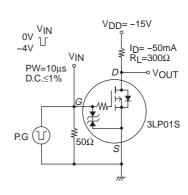
Parameter	Symbol	Conditions	Ratings			Unit
			min	typ	max	Oille
Total Gate Charge	Qg	VDS=-10V, VGS=-10V, ID=-100mA		1.43		nC
Gate-to-Source Charge	Qgs	V <sub>DS</sub> =-10V, V <sub>GS</sub> =-10V, I <sub>D</sub> =-100mA		0.18		nC
Gate-to-Drain "Miller" Charge	Qgd	VDS=-10V, VGS=-10V, ID=-100mA		0.25		nC
Diode Forward Voltage	VSD	IS=-100mA, VGS=0V		-0.83	-1.2	V

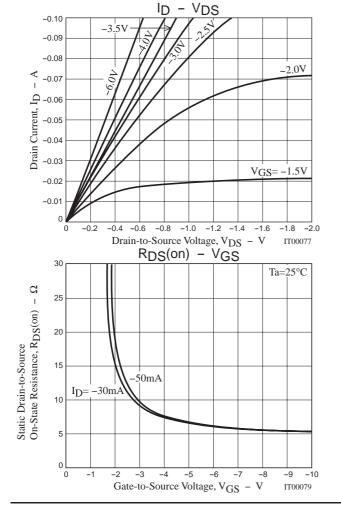
#### **Package Dimensions**

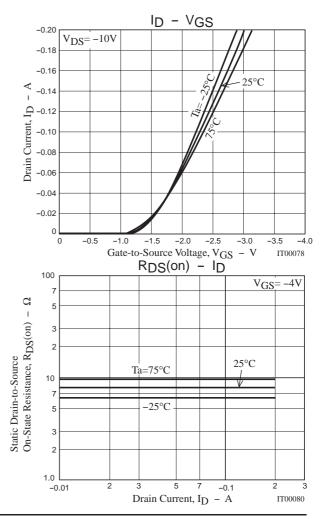
unit : mm 7027-004

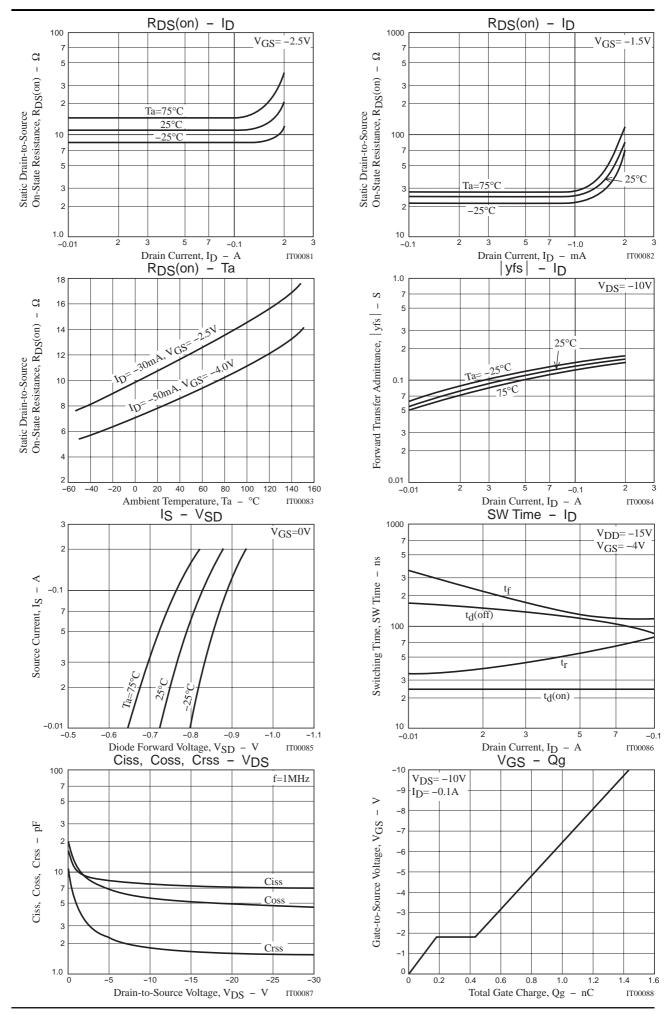


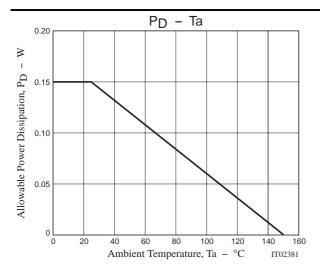
#### **Switching Time Test Circuit**











Note on usage: Since the 3LP01S is a MOSFET product, please avoid using this device in the vicinity of highly charged objects.

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